

Notice of References Cited	Application/Control No. 10/539,884		Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,413,966 A	11-1983	Mills et al.	425/84
*	B	US-4,531,705 A	07-1985	Nakagawa et al.	249/134
*	C	US-5,151,237 A	09-1992	Hettinga, Siebolt	264/257
*	D	US-5,407,342 A	04-1995	Boucher et al.	425/145
*	E	US-5,516,470 A	05-1996	Larsson, Owe G. T.	264/39
*	F	US-5,756,406 A	05-1998	Rittman et al.	442/117
*	G	US-5,866,025 A	02-1999	Kataoka et al.	249/114.1
*	H	US-2002/0130441 A1	09-2002	Robinson et al.	264/442
*	I	US-2006/0192309 A1	08-2006	Fukutani et al.	264/001.21
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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